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Automatized data analysis for surface XRD

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Understanding structure-property relationships in structural materials can only advance with state-of-the-art characterization. Probing the structure by x-rays has only recently become feasible, mostly by advances in nano-focusing. By scanning techniques, diffraction data of many different grains can be collected. My project aims at dealing with the data obtained from such experiments, in particular automated diffraction spot analysis and data reduction of 2D detector images using machine learning methods.

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